

### **AMENDMENTS TO THE SPECIFICATION**

Please replace paragraph [0045] with the following amended paragraph:

[0045] As shown, a lower substrate 100 has a first region 110 and a second region 120, on which a plurality of unit cells 102, and a plurality of first inspection pads 106 and second inspection pads 107 are formed, respectively. The plurality of unit cells 102 includes a plurality of gate and data lines 112 and 114, respectively, each of which is connected to the first inspection pads 106 through respective ones of gate and data shorting bars 116 (see FIG. 4D). The inspection pads 106 and 107 are electrically connected to the unit cells 102 and ~~positioned at an~~ are connected to end portions of a first inspection line 104 and a second inspection line 105. A higher voltage (+) is applied to the first inspection pad 106 connected to a gate and data shorting bars 116, and a lower voltage (-), a common voltage, is applied to the second inspection pad 107. To perform an ON/OFF inspection of a plurality of unit liquid crystal cells simultaneously, the unit cells positioned on the same side of a column along the axis of symmetry of the substrate and the same row are connected to the same pads 106 and 107 through the first and second inspection lines 104 and 105, respectively. Of course, other connecting structures can be applied to the present invention.

Please replace paragraph [0047] with the following amended paragraph:

[0047] As shown, the upper substrate 200 has a third region 130, on which a plurality of unit cells (not shown) composed of a color filter are formed, and a fourth region 140 having no unit cells. A common line 118 is provided at the third region 130 and is connected to the second inspection pads 107 (see FIG. 4D). Furthermore, a scribe key 210 is formed on a border between the third and fourth regions 130 and 140. In the following process, to

Application No.: 09/994,016  
Group Art Unit: 2871  
Reply to Office Action of April 22, 2003

Docket No.: 8733.546.00  
Reply Dated August 21, 2003  
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expose the inspection pad 106 (FIG. 3A) of the lower substrate, the hatched region 145 is cut along the scribe key 210, which can be formed on a plurality of positions of the border and preferably on the top and bottom of the right and left ends.